

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/549,866	<b>Applicant(s)/Patent under Reexamination</b> KAASTRA, SIMON
	<b>Examiner</b> Sang Y. Paik	<b>Art Unit</b> 3742

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner